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## N-Channel 30-V (D-S) MOSFET

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### Characteristics

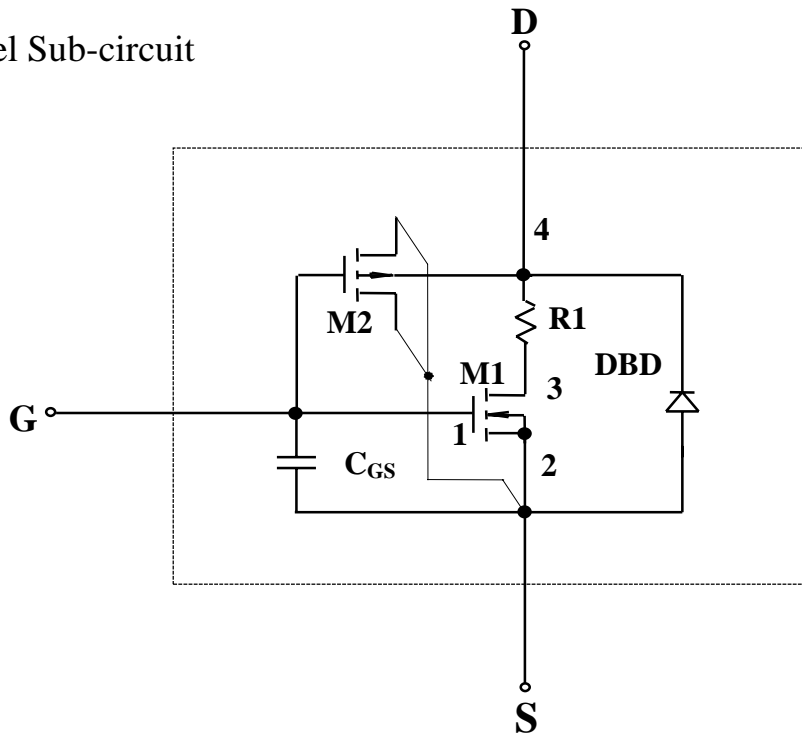
- N-channel Vertical DMOS
- Macro-Model (Sub-circuit)
- Level 3 MOS
- Applicable for Both Linear and Switch Mode
- Applicable Over a -55 to 125°C Temperature Range
- Models Gate Charge, Transient, and Diode Reverse Recovery Characteristics

### Description

The attached SPICE Model describes typical electrical characteristics of the n-channel vertical DMOS. The sub-circuit model was extracted and optimized over a 25°C to 125°C temperature range under pulse conditions for 0 to 10 volts gate drives. Saturated output impedance model accuracy has been maximized for gate biases near threshold. A novel gate-to-drain feedback

capacitor network is used to model gate charge characteristics while avoiding convergence problems of switched  $C_{gd}$  model. Model parameter values are optimized to provide a best fit to measure electrical data and are not intended as an exact physical description of a device.

### Model Sub-circuit



This document is intended as a SPICE modeling guideline and does not constitute a commercial product data sheet. Designers should refer to the appropriate data sheet of the same number for guaranteed specification limits.



Model Evaluation

N-Channel Device ( $T_J=25^\circ\text{C}$  Unless Otherwise Noted)

| Parameter                                     | Symbol       | Test Conditions   | Typical      | Unit     |
|---|--------------|---|--------------|----------|
| <b>Static</b>                                 |              |   |              |          |
| Gate Threshold Voltage                        | $V_{GS(th)}$ | $V_{DS} = V_{GS}, I_D = 250\mu\text{A}$   | <b>1.8</b>   | V        |
| On-State Drain Current <sup>a</sup>           | $I_{D(on)}$  | $V_{DS} = 5\text{V}, V_{GS} = 10\text{V}$   | <b>94</b>    | A        |
| Drain-Source On-State Resistance <sup>a</sup> | $r_{DS(on)}$ | $V_{GS} = 10\text{V}, I_D = 4.5\text{A}$  | <b>0.048</b> | $\Omega$ |
|   |              | $V_{GS} = 4.5\text{V}, I_D = 3.8\text{A}$   | <b>0.064</b> |          |
| Forward Transconductance <sup>a</sup>         | $g_{fs}$     | $V_{DS} = 10\text{V}, I_D = 4.5\text{A}$  | <b>9</b>     | S        |
| Diode Forward Voltage <sup>a</sup>            | $V_{SD}$     | $I_S = 1.7\text{A}, V_{GS} = 0\text{V}$   | <b>0.76</b>  | V        |
| <b>Dynamic <sup>b</sup></b>                   |              |   |              |          |
| Total Gate Charge                             | $Q_g$        | $V_{DS} = 15\text{V}, V_{GS} = 10\text{V}, I_D = 4.5\text{A}$                                   | <b>7.6</b>   | nC       |
| Gate-Source Charge                            | $Q_{gs}$     |   | <b>2.5</b>   |          |
| Gate-Drain Charge                             | $Q_{gd}$     |   | <b>1.5</b>   |          |
| Turn-On Delay Time                            | $t_{d(on)}$  | $V_{DD} = 15\text{V}, R_L = 15\Omega, I_D \cong 1\text{A}, V_{GEN} = 10\text{V}, R_G = 6\Omega$ | <b>9</b>     | ns       |
| Rise Time                                     | $t_r$        |   | <b>10</b>    |          |
| Turn-Off Delay Time                           | $t_{d(off)}$ |   | <b>28</b>    |          |
| Fall Time                                     | $t_f$        |   | <b>31</b>    |          |
| Source Drain Reverse Recovery Time            | $t_{rr}$     | $I_F = 1.7\text{A}, di/dt = 100\text{A}/\mu\text{s}$  | <b>45</b>    |          |

Notes:

- a) Pulse test; pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
- b) Guaranteed by design, not subject to production testing



# SPICE Device Model Si3454ADV

Comparison of Model with Measured Data  
 ( $T_J=25^\circ\text{C}$  Unless Otherwise Noted)

